



CS60N04 A4

General Description:

CS60N04A4, the silicon N-channel Enhanced VDMOSFETs, is obtained by advanced trench Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-252, which accords with the RoHS standard.

Features:

- l Rds(on) = 8.5mΩ @ Vgs=10V , ID=60A
- l High Performance Trench Technology for extremely low rds(on)
- l High Power and Current Handling Capability
- l 100% Avalanche Energy Test
- l 40V @ TJ = 150°

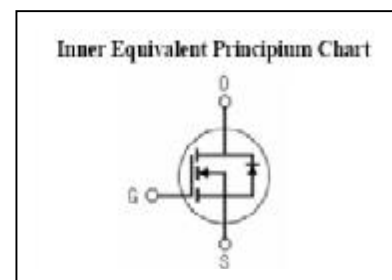
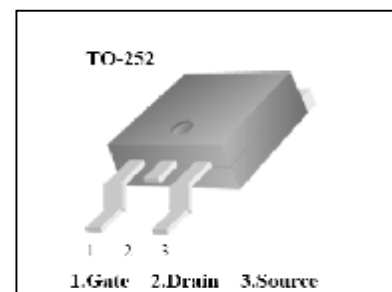
Applications:

Power switch circuit of adaptor and charger.

Absolute (Tc= 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V _{DSS}	Drain-to-Source Voltage	40	V
I _D	Continuous Drain Current	60	A
	Continuous Drain Current T _C = 100 °C	36	A
I _{DM} ^{a1}	Pulsed Drain Current	240	A
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS} ^{a2}	Single Pulse Avalanche Energy	190	mJ
dv/dt ^{a3}	Peak Diode Recovery dv/dt	15	V/ns
P _D	Power Dissipation	52	W
	Derating Factor above 25°C	0.4	W/°C
T _J , T _{stg}	Operating Junction and Storage Temperature Range	-55 to 150	°C
T _L	Maximum Temperature for Soldering	300	°C

V _{DSS}	40	V
I _D	60	A
P _D (T _C =25°C)	52	W
R _{DS(ON)Typ}	8.5	mΩ



OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$, reference 25°C	--	0.03	--	V/°C
I_{DSS}	Drain to Source Leakage Current	$V_{DS} = 40V, T_c = 25^\circ C$	--	--	1	μA
		$V_{DS} = 40V, T_a = 150^\circ C$	--	--	200	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=0V, I_D=250\mu A$	40	--	--	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{DS} = 0V, V_{GS} = -20V$	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=60A$	--	8.5	13	mΩ
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	--	2	V
Pulse width $tp \leq 300\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Trans conductance	$V_{DS} = 10V, I_D = 50A$	--	300	--	S
C_{iss}	Input Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ $f = 1.0MHz$	--	1920		pF
C_{oss}	Output Capacitance		--	150		
C_{rss}	Reverse Transfer Capacitance		--	115		

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 60A, V_{DD} = 20V$ $V_{GS} = 10V, R_G = 10\Omega$	--	15	--	ns
t_r	Rise Time		--	14	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	63	--	
t_f	Fall Time		--	20	--	
Q_g	Total Gate Charge	$I_D = 30A, V_{DD} = 32V$ $V_{GS} = 10V$	--	37.5		nC
Q_{gs}	Gate to Source Charge		--	10		
Q_{gd}	Gate to Drain ("Miller") Charge		--	5.47		

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	60	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	240	A
V_{SD}	Diode Forward Voltage	$V_{GS}=0V, I_S=60A,$	--	--	0.7	V
t_{rr}	Reverse Recovery Time	$I_S=20A, T_j = 25^\circ C$	--	48	--	ns
Q_{rr}	Reverse Recovery Charge	$di_f/dt=100A/us,$ $V_{GS}=0V$	--	6	--	nC
Pulse width $t_p \leq 300\mu s, \delta \leq 2\%$						

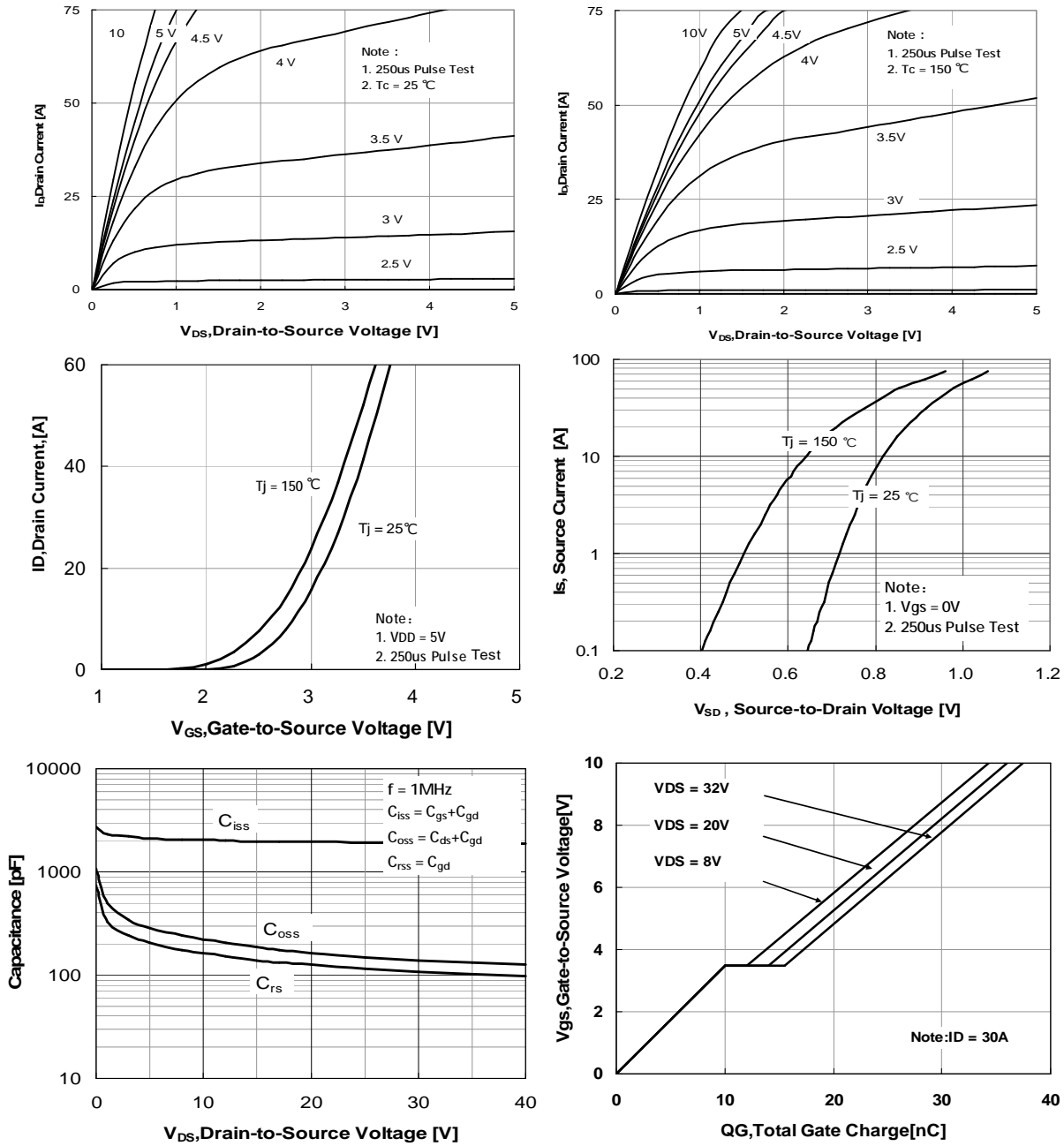
Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	2.4	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient	50	$^\circ C/W$

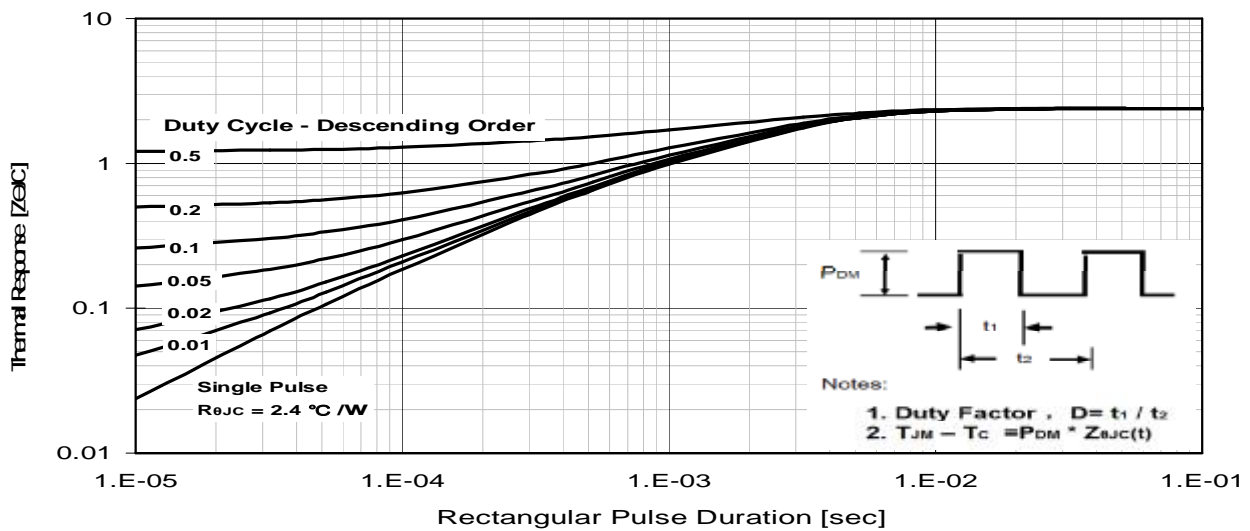
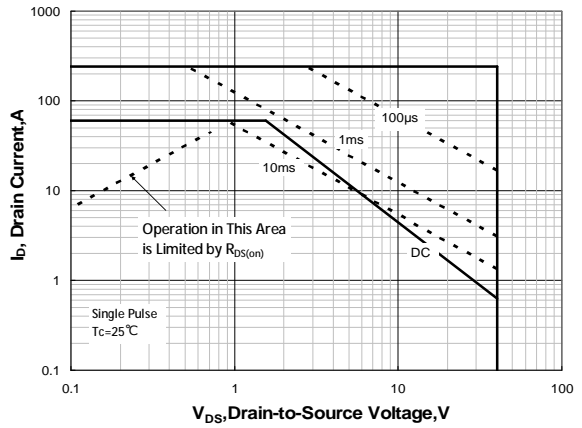
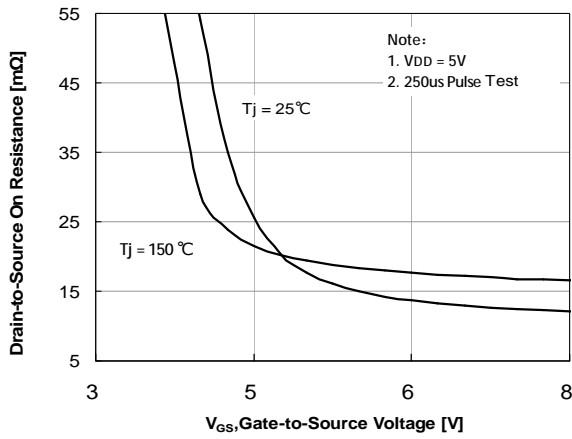
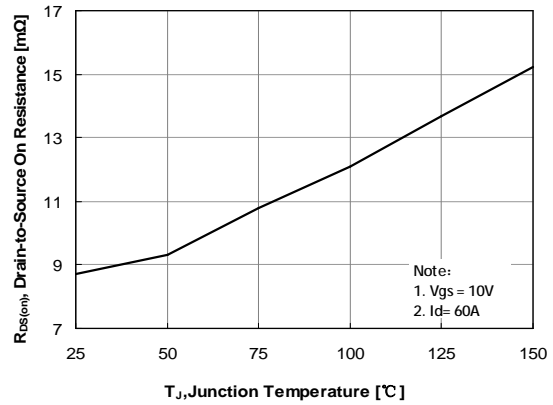
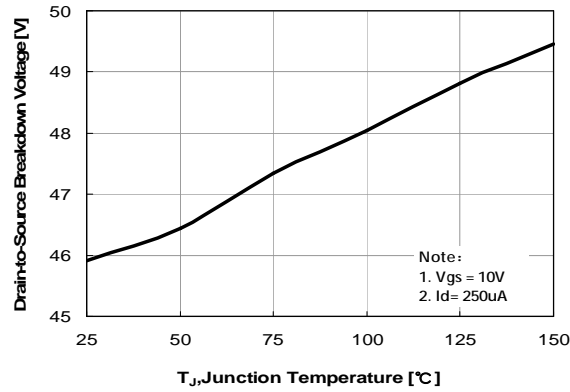
^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: $L=1mH, I_{as}=19.5A, R_g=25 \Omega, V_{dd}=30V, \text{Start } T_j=25^\circ C$

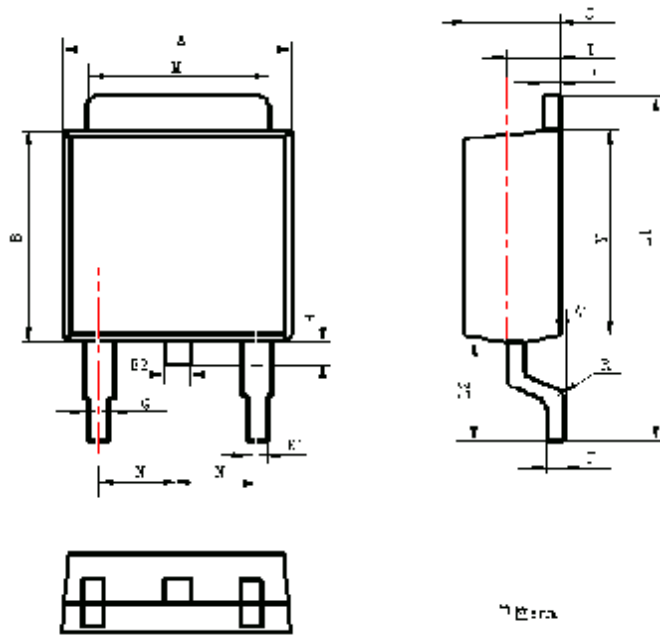
^{a3}: $I_{SD}=20A, di/dt \leq 200A/us, V_{DD} \leq BV_{DS}, \text{Start } T_j=25^\circ C$

Characteristics Curve:





Package Information



Items	Values(mm)	
	MIN	MAX
A	6.30	6.90
A1	0	0.13
B	5.70	6.30
C	2.10	2.50
D	0.30	0.60
E1	0.60	0.90
E2	0.70	1.00
F	0.30	0.60
G	0.70	1.00
L1	9.60	10.30
L2	2.70	3.10
H	0.60	1.00
M	5.10	5.50
N	2.09	2.49
R	0.3	
T	1.40	1.60
Y	5.10	6.30

TO-252 Package

**The name and content of poisonous and harmful material in products**

Part's Name	Hazardous Substance					
	Pb	Hg	Cd	Cr(VI)	PBB	PBDE
Limit	≤0.1%	≤0.1%	≤0.01%	≤0.1%	≤0.1%	≤0.1%
Lead Frame	○	○	○	○	○	○
Molding Compound	○	○	○	○	○	○
Chip	○	○	○	○	○	○
Wire Bonding	○	○	○	○	○	○
Solder	×	○	○	○	○	○
Note	○: means the hazardous material is under the criterion of SJ/T11363-2006. ×: means the hazardous material exceeds the criterion of SJ/T11363-2006. The plumbum element of solder exist in products presently, but within the allowed range of Eurogroup's RoHS.					

Warnings

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. It is suggested to be used under 80 percent of the maximum ratings of the device.
2. When installing the heatsink, please pay attention to the torsional moment and the smoothness of the heatsink.
3. VDMOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. This publication is made by Huajing Microelectronics and subject to regular change without notice.

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